

Diode EMCON 4 Medium Power Chip

FEATURES:

- 1200V EMCON 4 technology
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

• low / medium power modules



Applications:

• low / medium power drives

Chip Type	V_R	I _F	Die Size	Package
IDC40D120T6M	1200V	75A	6.30 x 6.30 mm ²	sawn on foil

MECHANICAL PARAMETER:

Raster size	6.30 x 6.30				
Area total / active	39.69 / 29.98	mm^2			
Anode pad size	5.346 x 5.346				
Thickness	110	μm			
Wafer size	150	mm			
Flat position	180	deg			
Max. possible chips per wafer	367 pcs				
Passivation frontside	Photoimide				
Pad metall	3200 nm AlSiCu				
Backside metall	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject ink dot size	Ø 0.65mm; max 1.2mm				
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



Maximum Ratings

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V_{RRM}		1200	٧	
Continuous forward current limited by T_{jmax}	I _F		1)	Α	
Maximum repetitive forward current limited by T _{jmax}	I _{FRM}		150		
Maximum junction and storage temperature	$T_{\rm vj,max}$, $T_{\rm stg}$		-40+175	°C	
Reverse bias safe operating area ²⁾ (RBSOA)	$I_{F,max} = 150A$, $V_{R,max} = 1200V$, $T_{Vj,op} \le 150$ °C, $P_{max} = $ tbd kW				

¹⁾ depending on thermal properties of assembly

Static Electrical Characteristics (tested on wafer), T_i =25 °C

Parameter	Symbol	Condi	Value			Unit	
	Cymbol	Conditions		min.	Тур.	max.	
Reverse leakage current	I_{R}	V _R =1200V	<i>T_j</i> =25 °C			14	μΑ
Cathode-Anode breakdown Voltage	V _{Br}	I _R =0.25mA	<i>T_j</i> =25°C	1200			V
Forward voltage drop	V_{F}	I _F =75A	<i>T_j</i> =25 °C	1.35	1.7	2.05	V

Dynamic Electrical Characteristics inductive load (not subject to production test - verified by design/characterization)

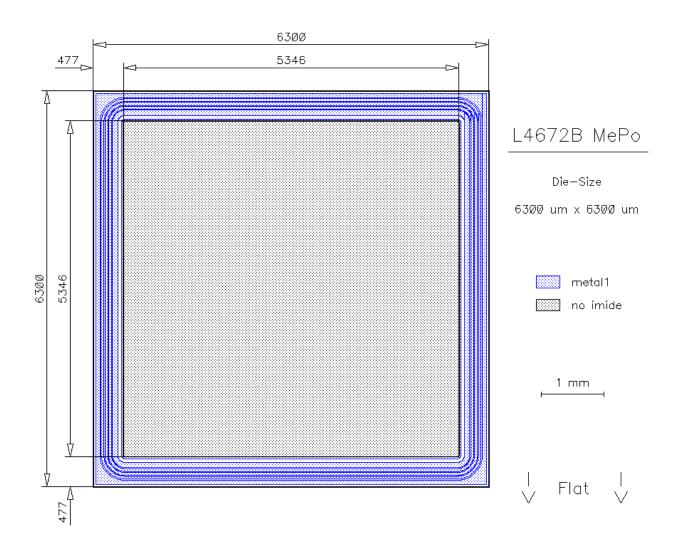
Parameter	Symbol	Conditions		Value 2)			Unit
raiailletei	Syllibol			min.	Тур.	max.	
Peak reverse recovery current	I _{RM}	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		А
Reverse recovery charge	Q _r	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_{j} = 25 ^{\circ}\text{C}$ $T_{j} = 125 ^{\circ}\text{C}$ $T_{j} = 150 ^{\circ}\text{C}$		tbd		μC
Reverse recovery energy	E _{rec}	$I_F=A$ di/dt=A/ms $V_R=V$ $V_{GE}=-15V$	$T_j = 25 ^{\circ}\text{C}$ $T_j = 125 ^{\circ}\text{C}$ $T_j = 150 ^{\circ}\text{C}$		tbd		mJ

²⁾ values also influenced by parasitic L- and C- in measurement and package.

²⁾ not subject to production test - verified by design/characterisation



CHIP DRAWING:





This chip data sheet refers to the device data sheet Description: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883 Test-Normen Villach/Prüffeld

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